

| | | | | |
|-----------------------------------|--|-------------------------|---|-------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination | |
| | | 10/785,619 | LOOK, CHRISTOPHER M. | |
| Examiner | | Art Unit | | Page 1 of 1 |
| Mike Stahl | | 2874 | | |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| | A | US-5,970,201 | 10-1999 | Anthony et al. | 385/140 |
| | B | US-6,801,679 | 10-2004 | Koh et al. | 385/14 |
| | C | US-2004/0208574 | 10-2004 | Kinoshita et al. | 398/83 |
| | D | US-5,627,925 | 05-1997 | Alferness et al. | 385/17 |
| | E | US-6,332,055 | 12-2001 | Hatayama et al. | 385/140 |
| | F | US-5,867,289 | 02-1999 | Gerstel et al. | 398/12 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.